



제 31회 한국반도체학술대회

The 31st Korean Conference on Semiconductors

2024년 1월 24일(수)-26일(금) | 경주화백컨벤션센터(HICO)

2024년 1월 25일(목), 09:00-10:45
Room K(205), 2층

G. Device & Process Modeling, Simulation and Reliability 분과

[TK1-G] Reliability & Power Device

좌장: 장지원 교수(연세대학교), 김성호 교수(세종대학교)

초청발표 TK1-G-1 09:00-09:30	Study on Reliability of Automotive Semiconductor Devices and Validation Technology Trends You-Cheol Jang HL Mando
TK1-G-2 09:30-09:45	Reliability Assessment of High-voltage FinFET Technology for RF Applications Kyoungwan Oh ¹ , Hyangwoo Kim ¹ , Wooyeol Maeng ² , Kangwook Park ² , Hyung-Jin Lee ² , Ju Hong Park ¹ , and Chang-Ki Baek ¹ ¹ POSTECH, ² Samsung Electronics Co., Ltd.
TK1-G-3 09:45-10:00	Numerical Investigation of GaN HMET Using Finite Element Method according to Process Parameters Na-Yeon Choi and Sung-Uk Zhang Digital Twin Laboratory, Dong-eui University
TK1-G-4 10:00-10:15	Simulation Study of a Full Turn-on RC-IGBT with Energy Loss Min Seok Jang ¹ , Jee Hun Jeong ¹ , Da Hui Yoo ¹ , Sung Mo Koo ² , and Ho Jun Lee ¹ ¹ Pusan National University, ² TRinno Technology Co., Ltd.
TK1-G-5 10:15-10:30	Wire Bonding 두께변화와 Die-attach Void에 따른 열 저항 변화 연구 Sang Min Nam and Sung-Uk Zhang Digital Twin Laboratory, Dong-Eui University
TK1-G-6 10:30-10:45	Compact Well RC Modeling Method for P1dB and Harmonic Distortion Simulation of the Multi-stacked Transistors on RF Switch Module Nakwon Yu, Jongmin Kim, Youngchul Kim, and Hyunchul Nah DB HiTek